Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/644,407	BAAN, JACOB DE
Examiner	Art Unit
KEVIN L. LEE	3753

	0540	OUED				
SEARCHED						
Class	Subclass	Date	Examiner			
137	615	9/26/2005	KL			
141	387 388					
441	4 5					

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST search- see search history printout	9/26/2005	KL		